# RENESAS

# R1LV0808ASB – 5SI, 7SI

# 8Mb Advanced LPSRAM (1024k word x 8bit)

REJ03C0394-0100 Rev.1.00 2009.12.08

#### Description

The R1LV0808ASB is a family of low voltage 8-Mbit static RAMs organized as 1,048,576-words by 8-bit, fabricated by Renesas's high-performance 0.15um CMOS and TFT technologies.

The R1LV08808ASB is suitable for memory applications where a simple interfacing, battery operating and battery backup are the important design objectives.

The R1LV0808ASB is packaged in a 44pin thin small outline mount device [11.76mm×18.41mm 44-pin plastic TSOP (II)]. It gives the best solution for a compaction of mounting area as well as flexibility of wiring pattern of printed circuit boards.

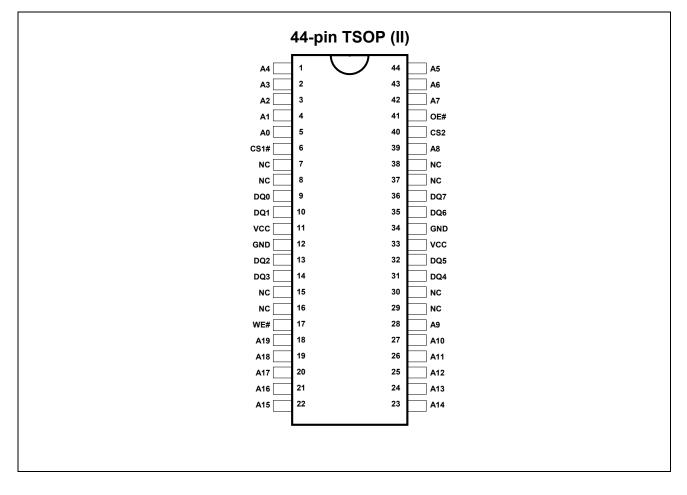
### Features

- Single 2.4-3.6V power supply
- Small stand-by current: 1.2µA (Vcc=3.0V, typ.)
- No clocks, No refresh
- All inputs and outputs are TTL compatible
- Easy memory expansion by CS1# andCS2
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE# prevents data contention in the I/O bus
- Operation temperature: -40 ~ +85°C
- •

Type No.	Power supply	Access time	Temperature Range	Package
R1LV0808ASB-5SI	2.7V to 3.6V	55 ns		11.76mm×18.41mm 44-pin plastic TSOP (II)
RILV0000A3B-33I	2.4V to 2.7V	70 ns	-40 ~ +85°C	(normal-bend type) (44P3F)
R1LV0808ASB-7SI	2.4V to 3.6V	70 ns		(normal-bend type) (441 SI )

#### Ordering information

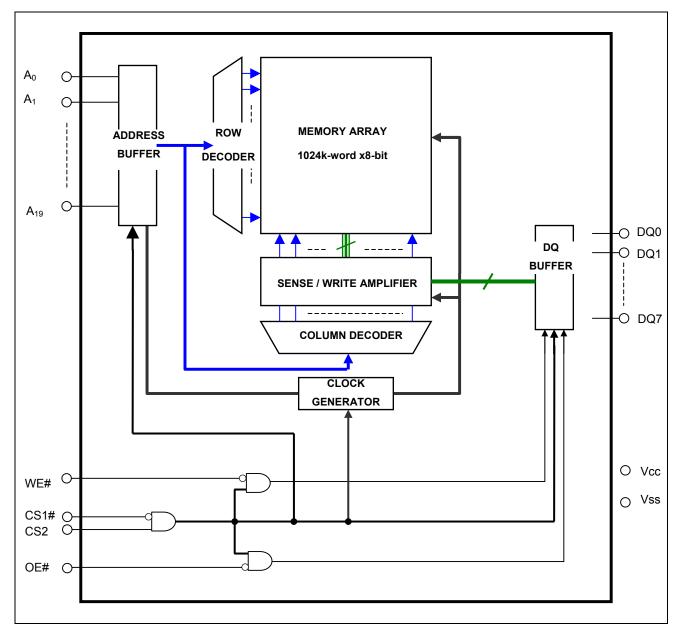
### Pin Arrangement



# Pin Description

Pin name	Function
Vcc	Power supply
Vss	Ground
A0 to A19	Address input (word mode)
DQ0 to DQ7	Data input/output
CS1#	Chip select 1
CS2	Chip select 2
WE#	Write enable
OE#	Output enable
NC	Non connection

# Block Diagram



# **Operation Table**

CS1#	CS2	WE#	OE#	DQ0~7	Operation
Х	L	Х	Х	High-Z	Stand-by
Н	Х	Х	Х	High-Z	Stand-by
L	Н	L	Х	Din	Write
L	Н	Н	L	Dout	Read
L	Н	Н	Н	High-Z	Output disable

Note 1. H:  $V_{IH} \quad L: V_{IL} \quad X: \, V_{IH} \text{ or } V_{IL}$ 

### Absolute Maximum Ratings

Parameter	Symbol	Value	unit
Power supply voltage relative to Vss	Vcc	-0.5 to +4.6	V
Terminal voltage on any pin relative to Vss	VT	-0.5 <sup>*1</sup> to Vcc+0.3 <sup>*2</sup>	V
Power dissipation	PT	0.7	W
Operation temperature	Topr	-40 to +85	°C
Storage temperature range	Tstg	-65 to 150	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Note 1. -3.0V in case of AC (Pulse width ≤30ns)

2. Maximum voltage is +4.6V

### **Recommend Operating Conditions**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Supply voltage	Vcc	2.4	3.0	3.6	V	-	
	Vss	0	0	0	V	-	
Input high voltage	V	2.0	-	Vcc+0.2	V	Vcc=2.4V to 2.7V	
	V <sub>IH</sub>	2.2	-	Vcc+0.2	V	Vcc=2.7V to 3.6V	
Input low voltage	V	-0.2	-	0.4	V	Vcc=2.4V to 2.7V	1
	VIL	-0.2	-	0.6	V	Vcc=2.7V to 3.6V	1
Ambient temperature range	Та	-40	-	+85	°C	-	

Note 1. -3.0V in case of AC (Pulse width ≤30ns)

### **DC** Characteristics

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions		
Input leakage current	I <sub>LI</sub>	-	-	1	μA	Vin = Vss to Vcc		
Output leakage current						CS1# =V <sub>IH</sub> or CS2 =V <sub>IL</sub> or		
	I <sub>LO</sub>	-	-	1	μA		or WE# =V <sub>IL</sub> ,	
						VI/O =Vs		
Average operating current	I <sub>CC1</sub>	-	20 <sup>*1</sup>	35	mA	-	e, duty =100%, II/O = 0mA <sub>IL</sub> , CS2 =V <sub>IH</sub> , Others = V <sub>IH</sub> /V <sub>IL</sub>	
	I <sub>CC2</sub>	-	2 <sup>*1</sup>	5	mA	Cycle =1µs, duty =100%, II/O = 0mA CS1# $\leq$ 0.2V, CS2 $\geq$ V <sub>CC</sub> -0.2V,		
							-0.2V, V <sub>IL</sub> ≤ 0.2V	
Standby current	I <sub>SB</sub>	-	-	1	mA	CS2 =V <sub>IL</sub>		
Standby current		-	1.2 <sup>*1</sup>	4	μA	~+25°C	Vin ≥ 0V	
		-	3 <sup>*2</sup>	6	μA	~+40°C	(1) $0V \le CS2 \le 0.2V$ or	
	I <sub>SB1</sub>	-	-	15	μA	~+70°C	(2) CS1# ≥ V <sub>CC</sub> -0.2V, CS2 ≥ V <sub>CC</sub> -0.2V	
		-	-	20	μΑ	~+85°C		
Output high voltage	V <sub>OH</sub>	2.4	-	-	V	I <sub>OH</sub> = -1mA Vcc≥2.7V		
	V <sub>OH2</sub>	2.0	-	-	V	I <sub>OH</sub> = -0.1	mA	
Output low voltage	V <sub>OL</sub>	-	-	0.4	V	I <sub>OL</sub> = 2mA Vcc≥2.7V		
	V <sub>OL2</sub>	-	-	0.4	V	I <sub>OL</sub> = 0.1n	nA	

Note 1.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+25°C), and not 100% tested. 2.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+40°C), and not 100% tested.

#### Capacitance

(Ta =25°C, f =1MHz)

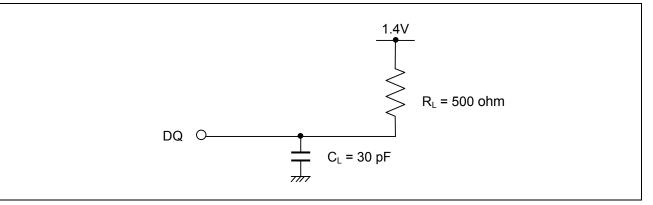
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Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions	Note
Input capacitance	C in	-	-	10	pF	Vin =0V	1
Input / output capacitance	C I/O	-	-	10	pF	V <sub>I/O</sub> =0V	1

Note 1.Typical parameter is sampled and not 100% tested.

#### **AC Characteristics**

Test Conditions (Vcc =  $2.4V \sim 3.6V$ , Ta =  $-40 \sim +85^{\circ}C$ )

- Input pulse levels: VIL = 0.4V, VIH = 2.4V (Vcc = 2.7V ~ 3.6 V)
   VIL = 0.4V, VIH = 2.2V (Vcc = 2.4V ~ 2.7 V)
- Input rise and fall times: 5ns
- Input and output timing reference level: 1.4V
- Output load: See figures (Including scope and jig)



# Read cycle

Parameter	Symbol		8ASB-5SI te 0)	R1LV0808ASB-7SI		Unit	Note
		Min.	Max.	Min.	Max.		
Read cycle time	t <sub>RC</sub>	55	-	70	-	ns	
Address access time	t <sub>AA</sub>	-	55	-	70	ns	
Chin coloct coccos time	t <sub>ACS1</sub>	-	55	-	70	ns	
Chip select access time	t <sub>ACS2</sub>	-	55	-	70	ns	
Output enable to output valid	t <sub>OE</sub>	-	30	-	35	ns	
Output hold from address change	t <sub>он</sub>	10	-	10	-	ns	
Chip select to output in low-Z	t <sub>CLZ1</sub>	10	-	10	-	ns	2,3
	t <sub>CLZ2</sub>	10	-	10	-	ns	2,3
Output enable to output in low-Z	t <sub>oLZ</sub>	5	-	5	-	ns	2,3
Chip deselect to output in high-Z	t <sub>CHZ1</sub>	0	20	0	25	ns	1,2,3
	t <sub>CHZ2</sub>	0	20	0	25	ns	1,2,3
Output disable to output in high-Z	t <sub>OHZ</sub>	0	20	0	25	ns	1,2,3

#### Write Cycle

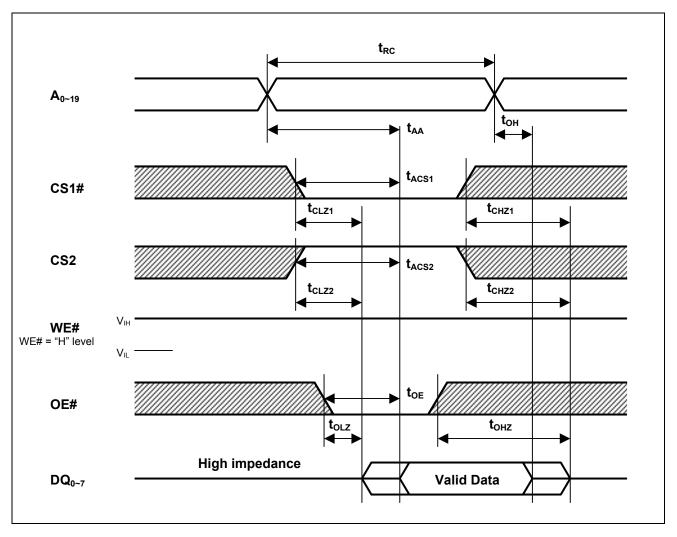
Parameter	Symbol		8ASB-5SI ote 0)	R1LV0808ASB-7SI		Unit	Note
		Min.	Max.	Min.	Max.		
Write cycle time	t <sub>wc</sub>	55	-	70	-	ns	
Address valid to end of write	t <sub>AW</sub>	50	-	65	-	ns	
Chip select to end of write	t <sub>CW</sub>	50	-	65	-	ns	5
Write pulse width	t <sub>WP</sub>	40	-	55	-	ns	4
Address setup time	t <sub>AS</sub>	0	-	0	-	ns	6
Write recovery time	t <sub>WR</sub>	0	-	0	-	ns	7
Data to write time overlap	t <sub>DW</sub>	25	-	35	-	ns	
Data hold from write time	t <sub>DH</sub>	0	-	0	-	ns	
Output enable from end of write	t <sub>ow</sub>	5	-	5	-	ns	2
Output disable to output in high-Z	t <sub>OHZ</sub>	0	20	0	25	ns	1,2
Write to output in high-Z	t <sub>WHZ</sub>	0	20	0	25	ns	1,2

Note 0. If Vcc is 2.4-2.7V, parameters of R1LV0808ASB-7SI (70ns) are applied.

- 1. t<sub>CHZ</sub>, t<sub>OHZ</sub>, t<sub>WHZ</sub> and t<sub>BHZ</sub> are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.
- 2. Typical parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition,  $t_{HZ}$  max is less than  $t_{LZ}$  min both for given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE#.
  A write begins at the latest transitions among CS1# going low, CS2 going high and WE# going low.
  A write ends at the earliest transitions among CS1# going high, CS2 going low and WE# going high.
  t<sub>WP</sub> is measured from the beginning of write to the end of write.
- 5. t<sub>CW</sub> is measured from the later of CS1# going low or CS2 going high to the end of write.
- 6.  $t_{AS}$  is measured the address valid to the beginning of write.
- 7. t<sub>WR</sub> is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle

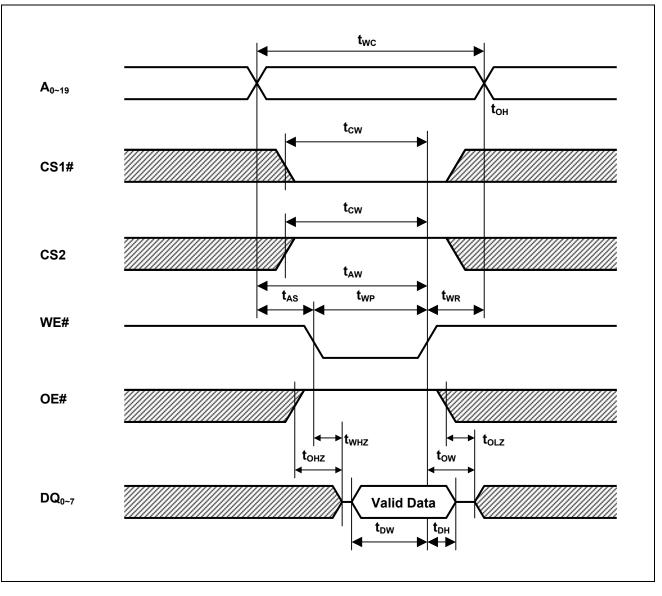
# **Timing Waveforms**

Read Cycle

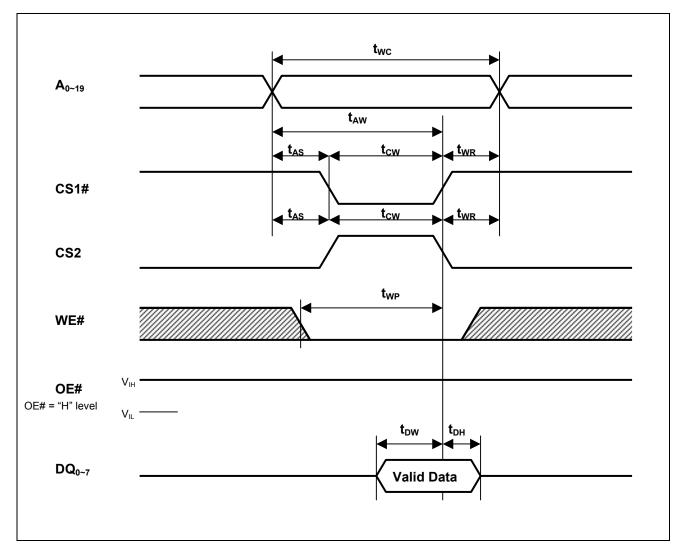


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### Write Cycle (1) (WE# CLOCK)



Write Cycle (2) (CS1#, CS2 CLOCK)



#### **Data Retention Characteristics**

Parameter	Symbol	Min.	Тур.	Max.	Unit	Test conditions <sup>*3</sup>		
V <sub>CC</sub> for data retention	V <sub>DR</sub>	1.5	-	3.6	V	Vin ≥ 0V (1) 0V ≤ CS2 ≤ 0.2V or (2) CS1# ≥ $V_{CC}$ -0.2V, CS2 ≥ $V_{CC}$ -0.2V		
Data retention current		-	1.2 <sup>*1</sup>	4	μA	~+25°C	Vcc=3.0V, Vin ≥ 0V	
	ICCDR	-	3 <sup>*2</sup>	6	μA	~+40°C	(1) 0V ≤ CS2 ≤ 0.2V or	
		-	-	15	μA	~+70°C	(2) CS1# ≥ V <sub>CC</sub> -0.2V, CS2 ≥ V <sub>CC</sub> -0.2V	
		-	-	20	μA	~+85°C		
Chip select to data retention time	t <sub>CDR</sub>	0	-	-	ns	See reter	tion waveform	
Operation recovery time	t <sub>R</sub>	5	-	-	ms	See retention waveform.		

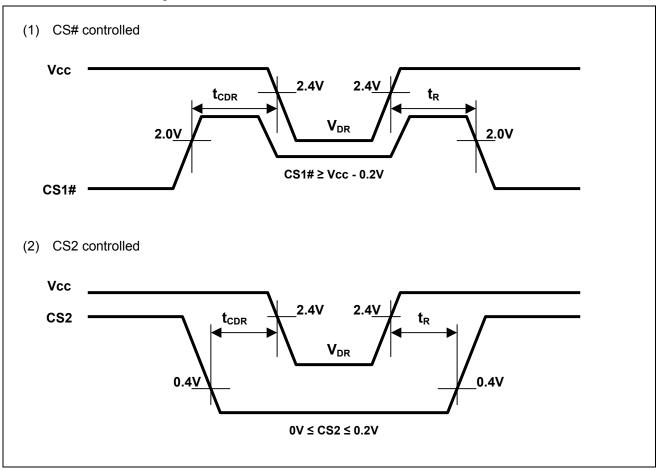
Note 1.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+25°C), and not 100% tested.

2.Typical parameter indicates the value for the center of distribution at 3.0V(Ta=+40°C), and not 100% tested. 3.CS2 controls address buffer, WE# buffer, CS1# Buffer, OE# buffer and Din buffer.

If CS2 controls data retention mode, Vin levels (address, WE#, OE #, DQ) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be CS2  $\ge$  V<sub>CC</sub>-0.2V or 0V  $\le$  CS2  $\le$  0.2V.

The other inputs levels (address, WE#, OE#, DQ) can be in the high impedance state.

### Data Retention Timing Waveforms



### RenesasTechnology Corp. sales Strategic Planning Div. Nippon Bldg., 2-6-2, Ohte-machi, Chiyoda-ku, Tokyo 100-0004, Japan

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